Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/708,986	CHEN ET AL.
Examiner	Art Unit
Rita Leykin	2837

SEARCHED				
Class	Subclass	Date	Examiner	
318	254	4/28/2005	R.L.	
	434			
	439			
	432			
	635			
	678			
	681			
363	95	·		
	97			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
318	254	4/28/2005	R.L.		
	438				
	434				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPAT,DERWENT,EPO,JPO USPGPUB	4/28/2005	R.L.		
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